

SJ-FET

TSK80R240S1/TSA80R240S1 800V N-Channel MOSFET

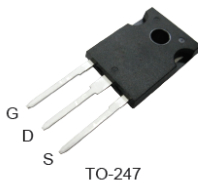
Description

SJ-FET is new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance. This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. SJ-FET is suitable for various AC/DC power conversion in switching mode operation for higher efficiency.

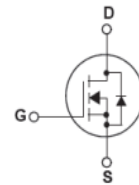
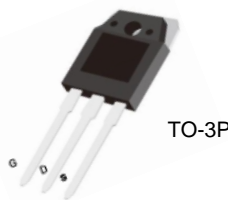
Features

- Multi-Epi process SJ-FET
- 850V @T_J = 150 °C
- Typ. RDS(on) = 0.22Ω
- Ultra Low Gate Charge (typ. Q_g = 27.5nC)
- 100% avalanche tested

TSK80R240S1



TSA80R240S1



Absolute Maximum Ratings

Symbol	Parameter	TSK_A80R240S1	Unit
V _{DSS}	Drain-Source Voltage	800	V
I _D	Drain Current		
	-Continuous (TC = 25°C)	18.4*	A
	-Continuous (TC = 100°C)	11.6*	
I _{DM}	Drain Current – Pulsed (Note 1)	51*	A
V _{GSS}	Gate-Source voltage	±30	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	485	mJ
I _{AR}	Avalanche Current (Note 1)	3.5	A
E _{AR}	Repetitive Avalanche Energy (Note 1)	1	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	15	V/ns
dVds/dt	Drain Source voltage slope (Vds=640V)	50	V/ns
P _D	Power Dissipation (TC = 25°C)	151	W
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	°C

* Drain current limited by maximum junction temperature. Maximum duty cycle D=0.75.

Thermal Characteristics

Symbol	Parameter	TSK_A80R240S1	Unit
R _{θJC}	Thermal Resistance, Junction-to-Case	0.83	°C/W
R _{θCS}	Thermal Resistance, Case-to-Sink Typ.	0.5	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient	62	°C/W



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Electrical Characteristics TC = 25°C unless otherwise noted

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Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA, T _J = 25°C	800	-	-	V
		V _{GS} = 0V, I _D = 250μA, T _J = 150°C	-	850	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.6	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 800V, V _{GS} = 0V -T _J = 150°C	-	- 10	1 -	μA μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30V, V _{DS} = 0V	-	-	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30V, V _{DS} = 0V	-	-	-100	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.5	3.5	4.5	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10V, I _D = 9A	-	0.22	0.26	Ω
g _{FS}	Forward Trans conductance	V _{DS} = 40V, I _D = 18A	-	19	-	S
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz	-	1290	-	pF
C _{OSS}	Output Capacitance		-	380	-	pF
C _{rSS}	Reverse Transfer Capacitance		-	22	-	pF
Switching Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DD} = 400V, I _D = 10A R _G = 25Ω (Note 4)	-	40	-	ns
t _r	Turn-On Rise Time		-	21	-	ns
t _{d(off)}	Turn-Off Delay Time		-	139	-	ns
t _f	Turn-Off Fall Time		-	21	-	ns
Q _g	Total Gate Charge	V _{DS} = 450V, I _D = 10A V _{GS} = 10V (Note 4)	-	27.5	-	nC
Q _{gs}	Gate-Source Charge		-	6.3	-	nC
Q _{gd}	Gate-Drain Charge		-	11.2	-	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Drain-Source Diode Forward Current		-	-	18	A
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		-	-	51	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0V, I _F = 20A	-	1	1.5	V
t _{rr}	Reverse Recovery Time	V _R = 400V, V _{GS} = 0V, I _F = 20A, di _F /dt = 100A/μs	-	710	-	ns
Q _{rr}	Reverse Recovery Charge		-	13	-	μC
I _{rrm}	Peak reverse recovery Current		-	33	-	A

NOTES:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. I_{AS} = 3.5A, V_{DD} = 50V, Starting T_J = 25 °C
3. I_{SD} ≤ I_D, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25 °C
4. Essentially Independent of Operating Temperature Typical Characteristics

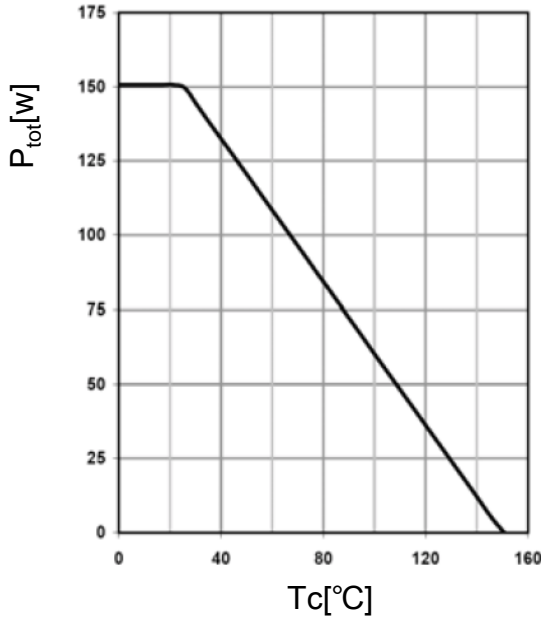


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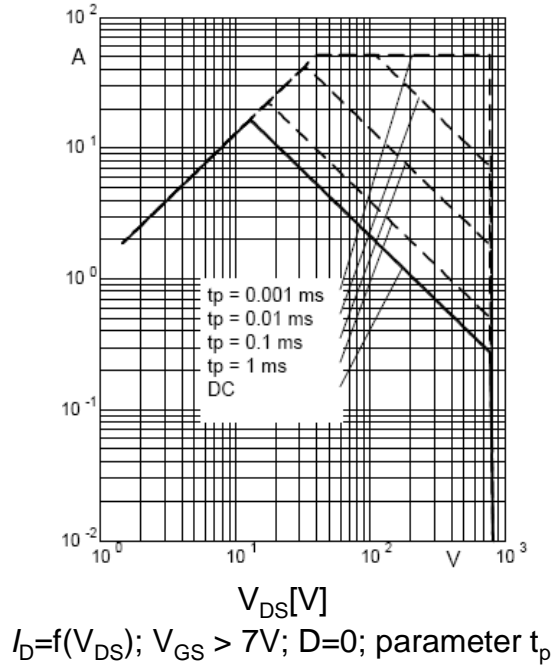
Typical Performance Characteristics

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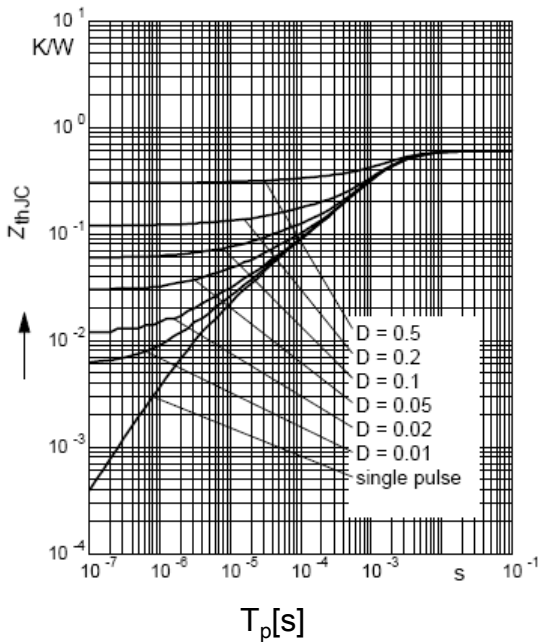
Power dissipation



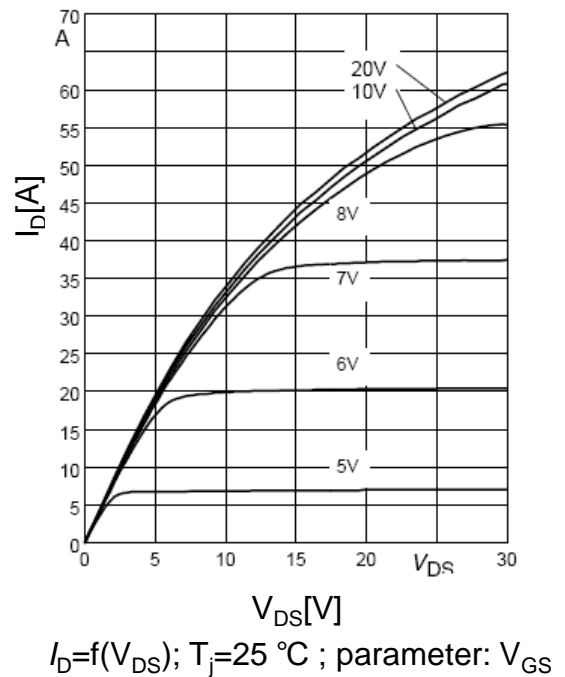
Safe operating area $T_C=25^\circ\text{C}$



Max. transient thermal impedance



Typ. output characteristics $T_j=25^\circ\text{C}$

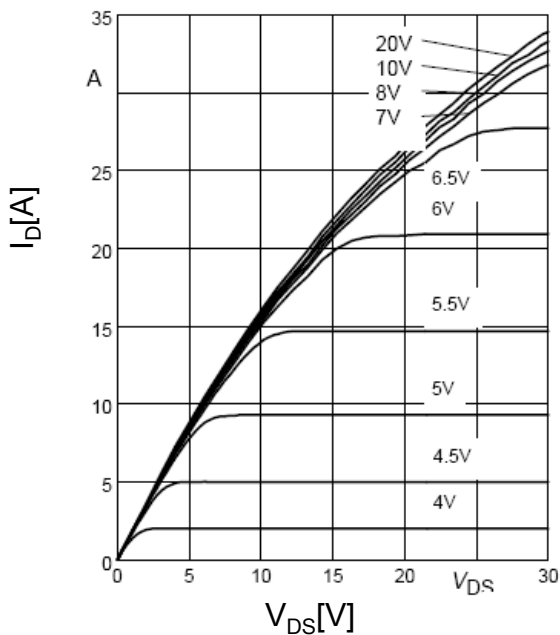




Truesemi® Typical Performance Characteristics

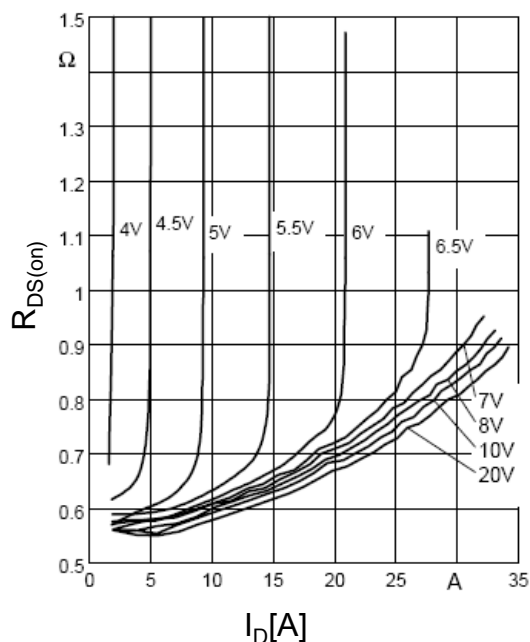
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Typ. output characteristics



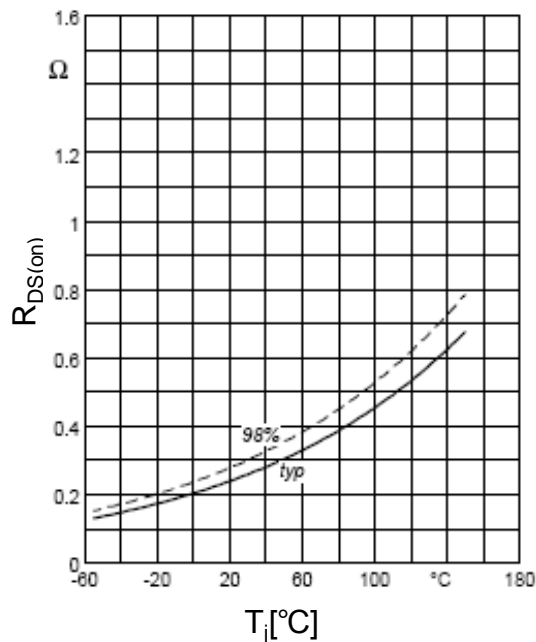
$I_D = f(V_{DS}); T_j = 150^\circ\text{C}; \text{parameter: } V_{GS}$

Typ. drain-source on-state resistance



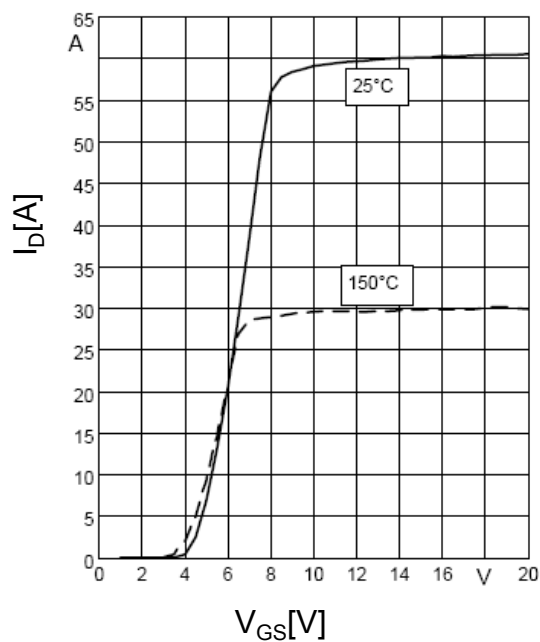
$R_{DS(on)} = f(I_D); T_j = 150^\circ\text{C}; \text{parameter: } V_{GS}$

Typ. drain-source on-state resistance



$R_{DS(on)} = f(T_j); I_D = 11\text{ A}; V_{GS} = 10\text{ V}$

Typ. transfer characteristics



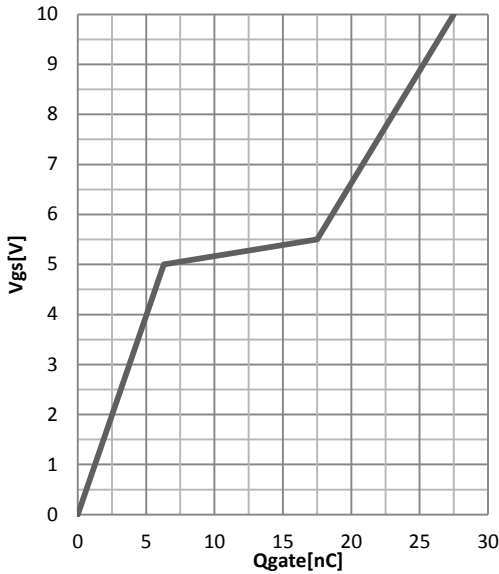
$I_D = f(V_{GS}); V_{DS} = 40\text{ V}$



Typical Performance Characteristics

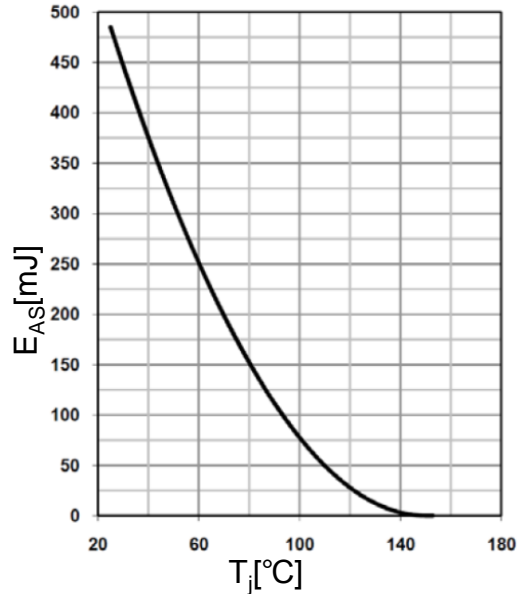
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Typ. gate charge



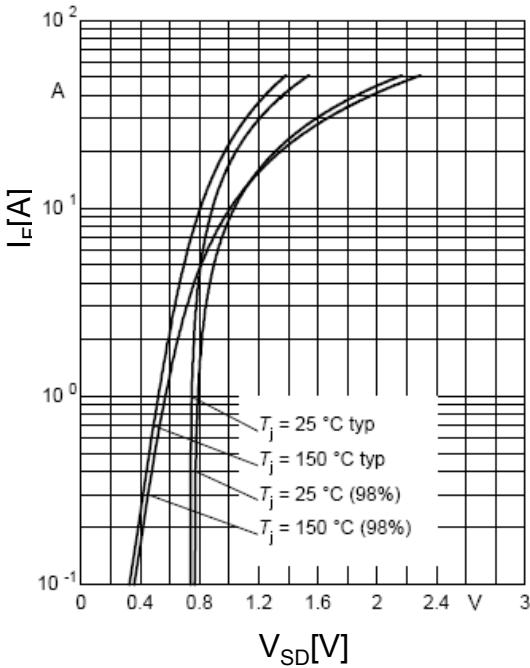
$V_{GS}=f(Q_g)$, $I_D=18$ A pulsed

Avalanche energy



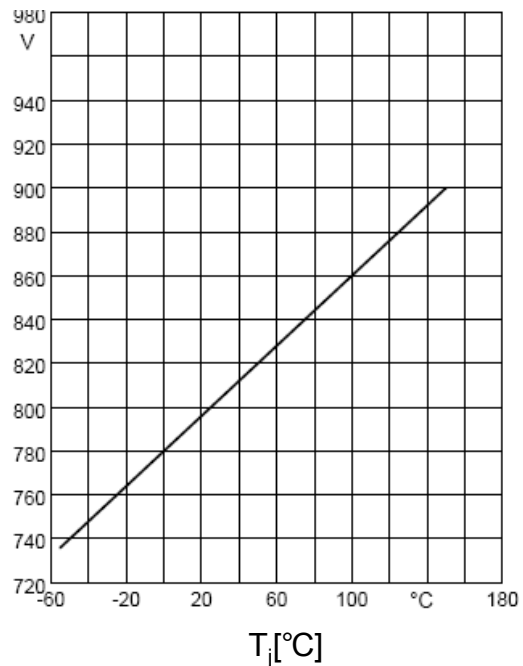
$E_{AS}=f(T_j)$; $I_D=3.5$ A; $V_{DD}=50$ V

Forward characteristics of reverse diode



$I_F=f(V_{SD})$; parameter: T_j

Drain-source breakdown voltage



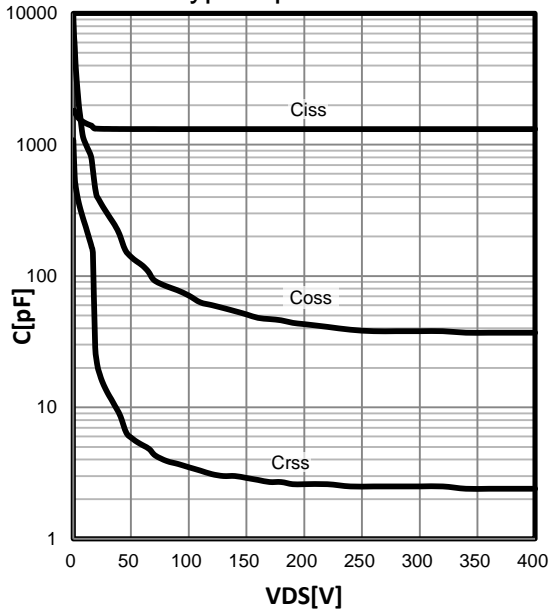
$V_{BR(DSS)}=f(T_j)$; $I_D=1.0$ mA



Truesemi® Typical Performance Characteristics

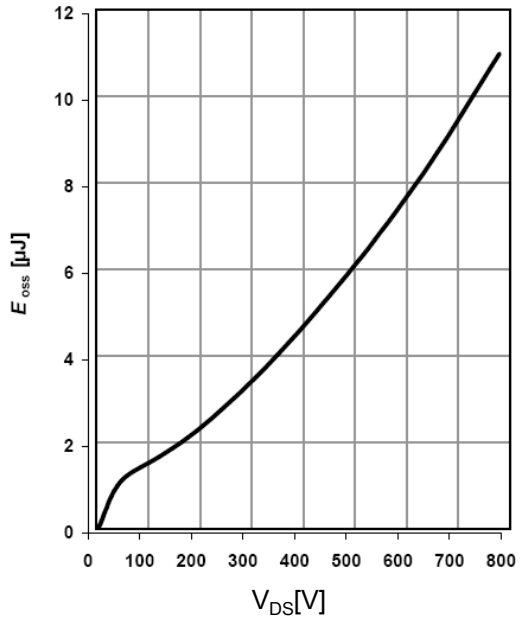
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Typ. capacitances

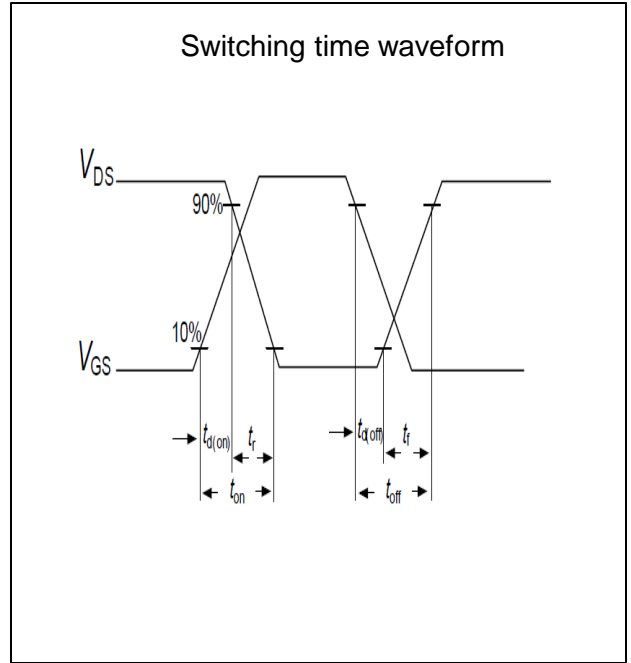
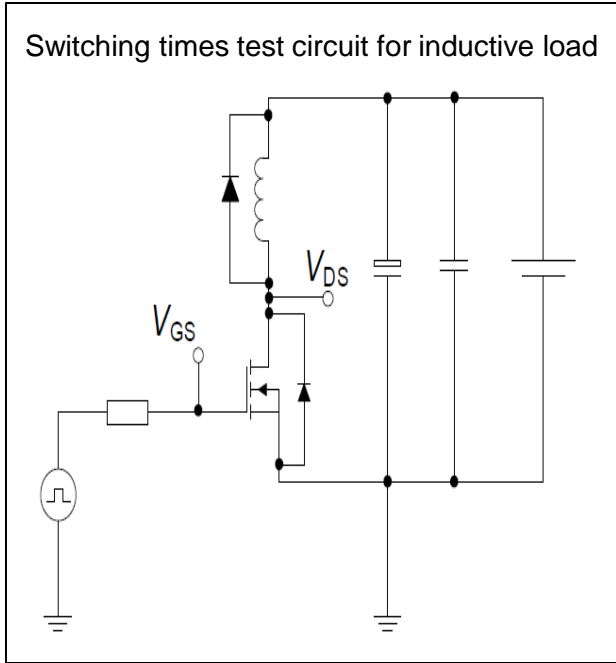
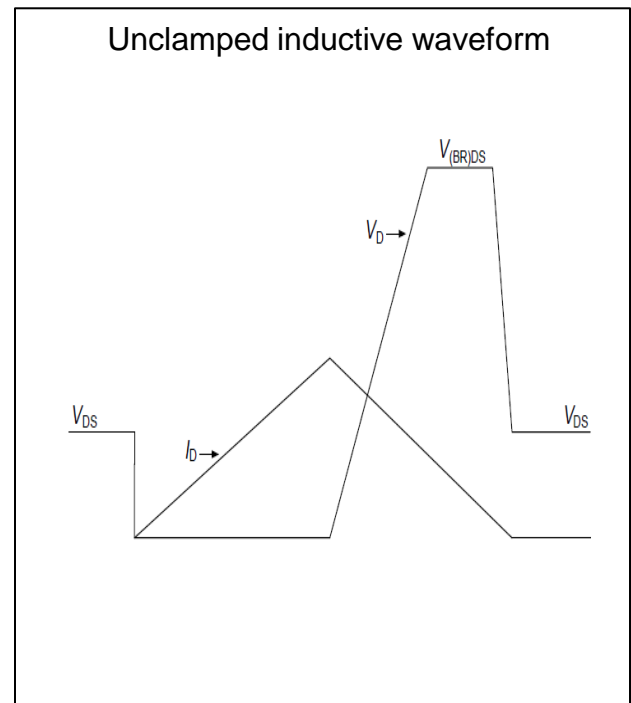
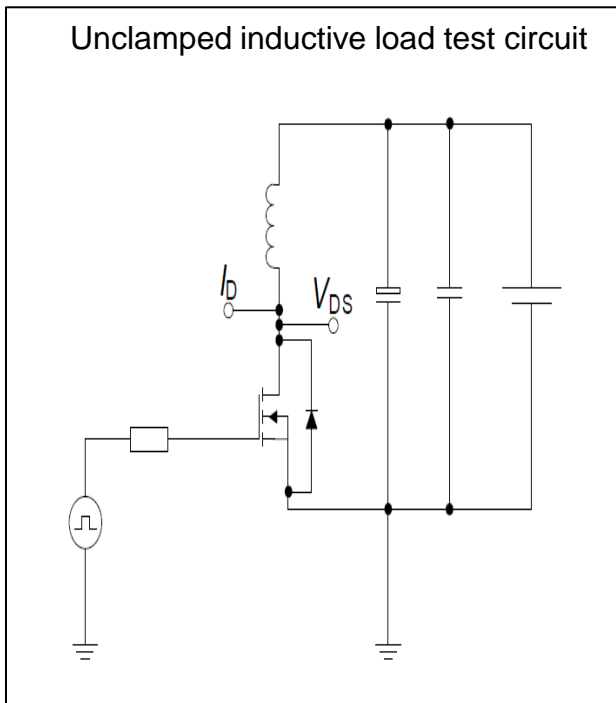


$$C=f(V_{DS}); V_{GS}=0\text{ V}; f=1\text{ MHz}$$

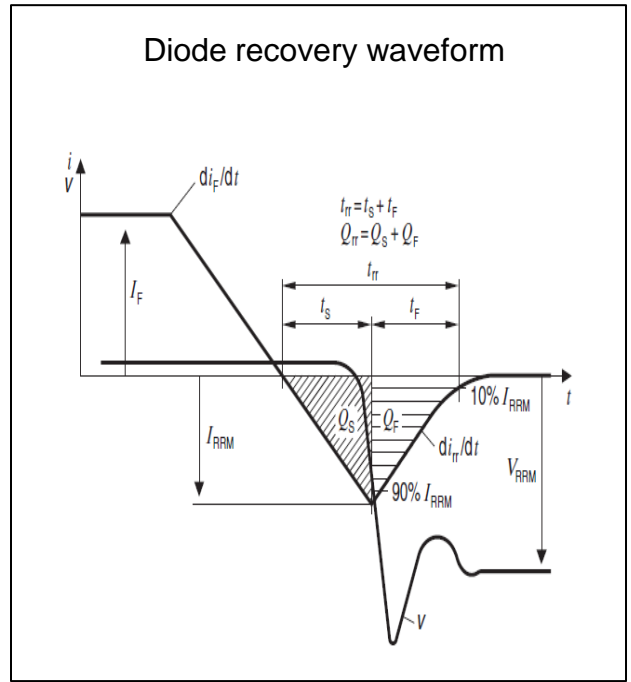
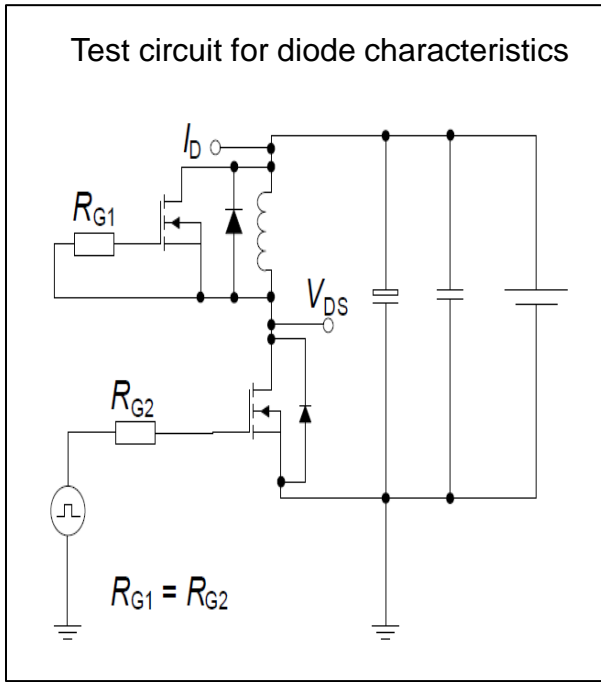
Typ. Coss stored energy



$$E_{OSS}=f(V_{DS})$$

Switching times test circuit and waveform for inductive load

Unclamped inductive load test circuit and waveform


Test circuit and waveform for diode characteristics





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